

# ISO 18114:2021 (E)

## Surface chemical analysis — Secondary-ion mass spectrometry — Determination of relative sensitivity factors from ion-implanted reference materials

---

### Contents

|   |                                   |
|---|-----------------------------------|
|   | Foreword                          |
|   | Introduction                      |
| 1 | Scope                             |
| 2 | Normative references              |
| 3 | Terms and definitions             |
| 4 | Symbols and abbreviated terms     |
| 5 | Principle                         |
| 6 | Apparatus                         |
| 7 | Ion-implanted reference materials |
| 8 | Procedure                         |
| 9 | Test report                       |

Page count: 4